

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)
**IEEE Xplore®**  
 RELEASE 1.8

 Welcome  
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Tables of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

**IEEE Enterprise**

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

 Your search matched **5** of **1138071** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.


☐ Check to search within this result set

**Results Key:**
**JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

**1 Carbon nanotube networks: applications on flexible substrates**
*Novak, J.P.; Perkins, F.K.; Snow, E.S.;*

Semiconductor Device Research Symposium, 2003 International , 10-12 Dec.

Pages:414

[\[Abstract\]](#)   [\[PDF Full-Text \(161 KB\)\]](#)   IEEE CNF

**2 Random networks of single-wall carbon nanotubes: electronic and sensor applications**
*Snow, E.S.; Novak, J.P.; Park, D.;*

Device Research Conference, 2003 , 23-25 June 2003

Pages:179 - 180

[\[Abstract\]](#)   [\[PDF Full-Text \(306 KB\)\]](#)   IEEE CNF

**3 Strategy of nanotechnology R & D in Japan -recent topics of nanotechnology research at Fujitsu**
*Yokoyama, N.;*

VLSI Technology, Systems, and Applications, 2003 International Symposium on , 2003

Pages:259 - 260

[\[Abstract\]](#)   [\[PDF Full-Text \(239 KB\)\]](#)   IEEE CNF

**4 Regularly coiled carbon nanotubes**
*Biro, L.P.; Mark, G.I.; Lambin, P.;*

Nanotechnology, IEEE Transactions on , Volume: 2 , Issue: 4 , Dec. 2003

Pages:362 - 367